


<b>Search Notes</b>  	<b>Application/Control No.</b>  10565688	<b>Applicant(s)/Patent Under Reexamination</b>  MIYANO ET AL.
	<b>Examiner</b>  Bui-Pho, Pascal M	<b>Art Unit</b>  2878

SEARCHED			
Class	Subclass	Date	Examiner
250	234, 227.11, 227.2, 227.24, 227.26, 559.06, 559.29	10/25/07	pmb
359	664	10/25/07	pmb
73	105	10/25/07	pmb

SEARCH NOTES		
Search Notes	Date	Examiner
Classes 250, 73, 385, 359 - East Search (USPAT, USPGPUB, USOCR, EPO, JPO, DERWENT, IBM, TDB)	10/25/07	pmb
Consulted with Patrick Lee (Class 250)	10/25/07	pmb

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner